

Title (en)

METHODS AND SYSTEMS FOR CHARACTERIZATION OF AN X-RAY BEAM WITH HIGH SPATIAL RESOLUTION

Title (de)

VERFAHREN UND SYSTEME ZUR CHARAKTERISIERUNG EINES RÖNTGENSTRAHLS MIT HOHER RÄUMLICHER AUFLÖSUNG

Title (fr)

PROCÉDÉS ET SYSTÈMES PERMETTANT DE CARACTÉRISER UN FAISCEAU DE RAYONS X À HAUTE RÉOLUTION SPATIALE

Publication

EP 3622276 A4 20210324 (EN)

Application

EP 18799085 A 20180510

Priority

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Abstract (en)

[origin: US2018328868A1] Methods and systems for positioning a specimen and characterizing an x-ray beam incident onto the specimen in a Transmission, Small-Angle X-ray Scatterometry (T-SAXS) metrology system are described herein. A specimen positioning system locates a wafer vertically and actively positions the wafer in six degrees of freedom with respect to the x-ray illumination beam without attenuating the transmitted radiation. In some embodiments, a cylindrically shaped occlusion element is scanned across the illumination beam while the detected intensity of the transmitted flux is measured to precisely locate the beam center. In some other embodiments, a periodic calibration target is employed to precisely locate the beam center. The periodic calibration target includes one or more spatially defined zones having different periodic structures that diffract X-ray illumination light into distinct, measurable diffraction patterns.

IPC 8 full level

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CPC (source: EP IL KR US)

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Citation (search report)

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